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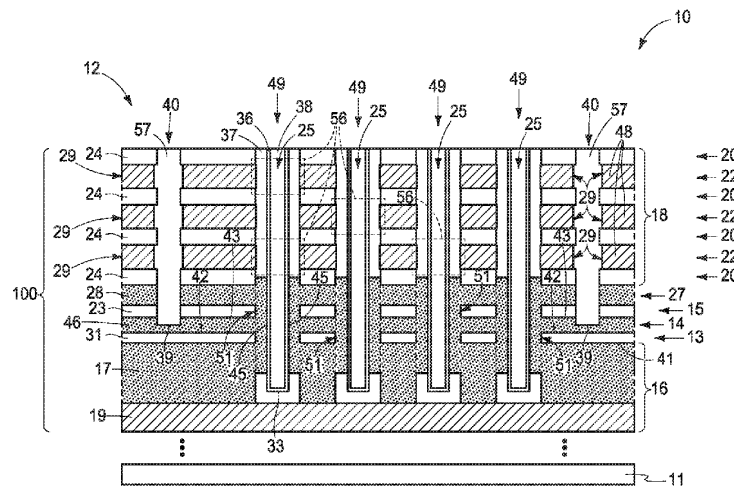


FIG. 28

(57) Abstract: A method used in forming a memory array comprising strings of memory cells comprises forming a stack comprising vertically- alternating insulative tiers and wordline tiers. First charge-blocking material is formed to extend elevationally along the vertically -alternating tiers. The first charge-blocking material has k of at least 7.0 and comprises a metal oxide. A second charge-blocking material is formed laterally inward of the first charge-blocking material. The second charge-blocking material has k less than 7.0. Storage material is formed laterally inward of the second charge-blocking material. Insulative charge-passage material is formed laterally inward of the storage material. Channel material is formed to extend elevationally along the insulative tiers and the wordline tiers laterally inward of the insulative charge-passage material. Structure embodiments are disclosed.

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